



ALPHA & OMEGA
SEMICONDUCTOR

AO3499

20V P-Channel MOSFET

General Description

- Low $R_{DS(ON)}$
- RoHS and Halogen-Free Compliant

Applications

- Load switch
- PWM

Product Summary

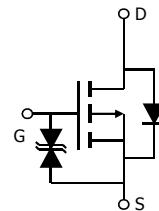
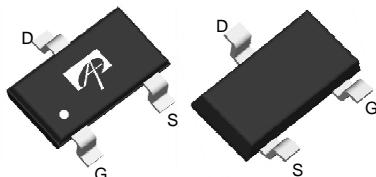
V_{DS}	-20V
I_D (at $V_{GS}=-10V$)	-3.5A
$R_{DS(ON)}$ (at $V_{GS}=-10V$)	< 85mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$)	< 102mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$)	< 140mΩ

Typical ESD protection

HBM Class 2



SOT23
Top View Bottom View



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-20	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	-3.5	A
$T_A=70^\circ\text{C}$		-2.8	
Pulsed Drain Current ^C	I_{DM}	-17	
Power Dissipation ^B	P_D	1.4	W
$T_A=70^\circ\text{C}$		0.9	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	65	90	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		85	125	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	43	60	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units	
STATIC PARAMETERS							
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-20			V	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA	
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}= \pm 12\text{V}$			± 10	μA	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-0.5	-0.85	-1.2	V	
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-4.5\text{V}$, $V_{DS}=-5\text{V}$	-17			A	
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$, $I_D=-3.5\text{A}$ $T_J=125^\circ\text{C}$		71 99	85 119	$\text{m}\Omega$	
		$V_{GS}=-4.5\text{V}$, $I_D=-3\text{A}$			85	$\text{m}\Omega$	
		$V_{GS}=-2.5\text{V}$, $I_D=-1\text{A}$			112	$\text{m}\Omega$	
		$V_{GS}=-1.8\text{V}$, $I_D=-0.5\text{A}$			168	$\text{m}\Omega$	
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-3.5\text{A}$			8.6	S	
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$			-0.76	-1	V
I_S	Maximum Body-Diode Continuous Current				-1.5	A	
DYNAMIC PARAMETERS							
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-10\text{V}$, $f=1\text{MHz}$			325	pF	
C_{oss}	Output Capacitance				63	pF	
C_{rss}	Reverse Transfer Capacitance				37	pF	
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$			11.2	Ω	
SWITCHING PARAMETERS							
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}$, $V_{DS}=-10\text{V}$, $I_D=-3.5\text{A}$			3	nC	
Q_{gs}	Gate Source Charge				0.6	nC	
Q_{gd}	Gate Drain Charge				1.1	nC	
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}$, $V_{DS}=-10\text{V}$, $R_L=2.8\Omega$, $R_{\text{GEN}}=3\Omega$			11	ns	
t_r	Turn-On Rise Time				5.5	ns	
$t_{\text{D(off)}}$	Turn-Off Delay Time				22	ns	
t_f	Turn-Off Fall Time				8	ns	
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-3.5\text{A}$, $di/dt=100\text{A}/\mu\text{s}$			11	ns	
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-3.5\text{A}$, $di/dt=100\text{A}/\mu\text{s}$			4.3	nC	

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leqslant 10\text{s}$ junction-to-ambient thermal resistance.

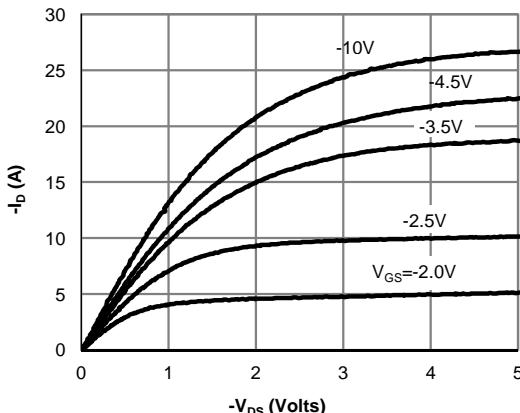
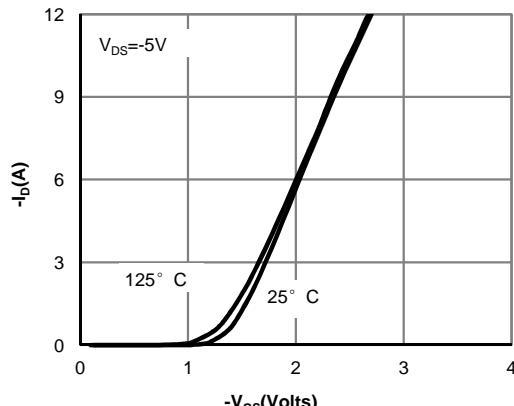
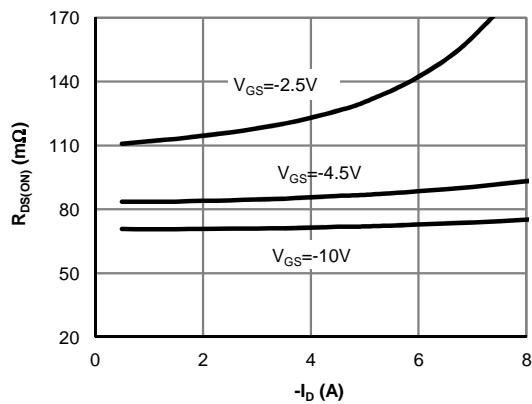
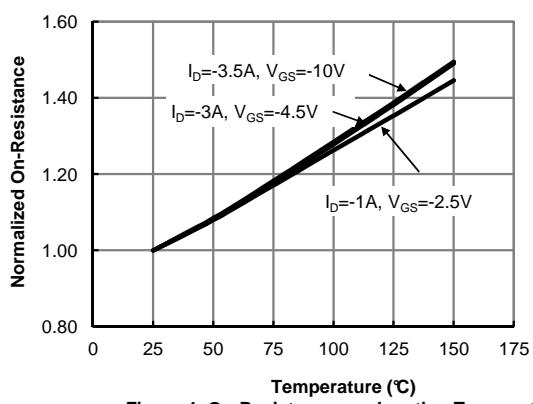
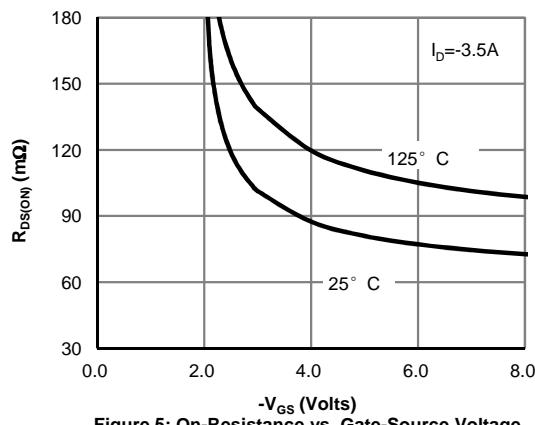
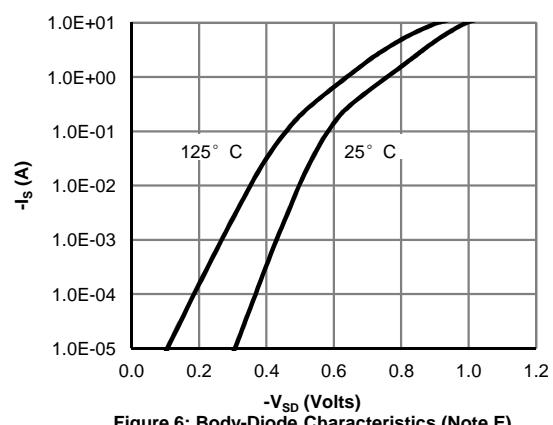
C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

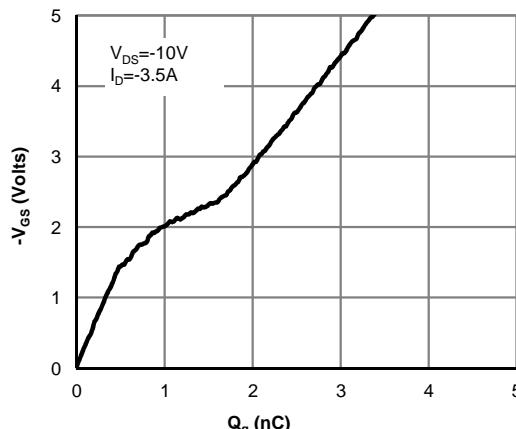
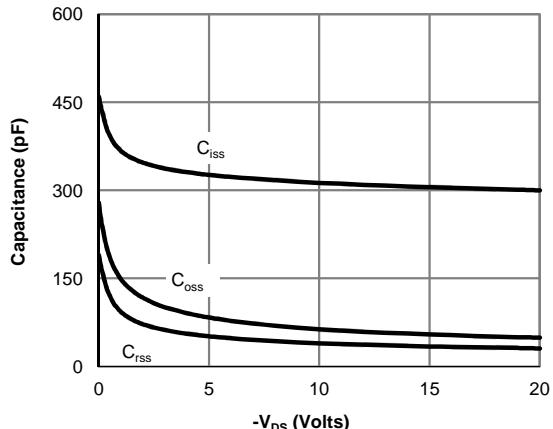
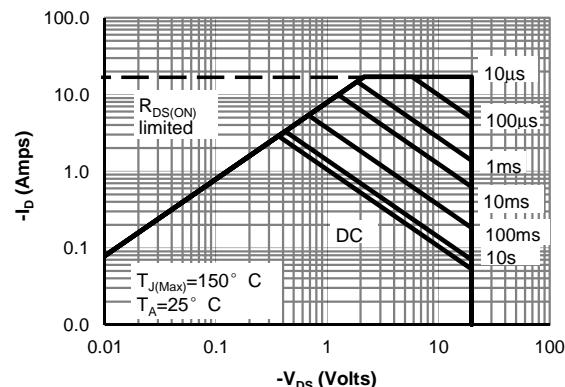
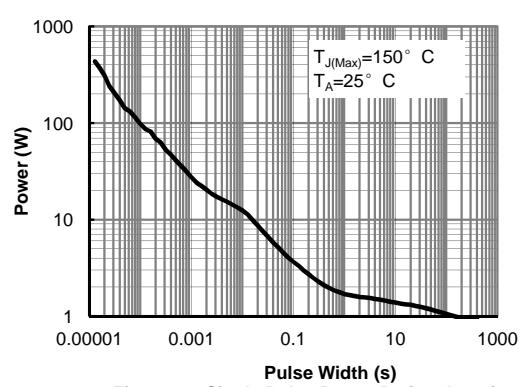
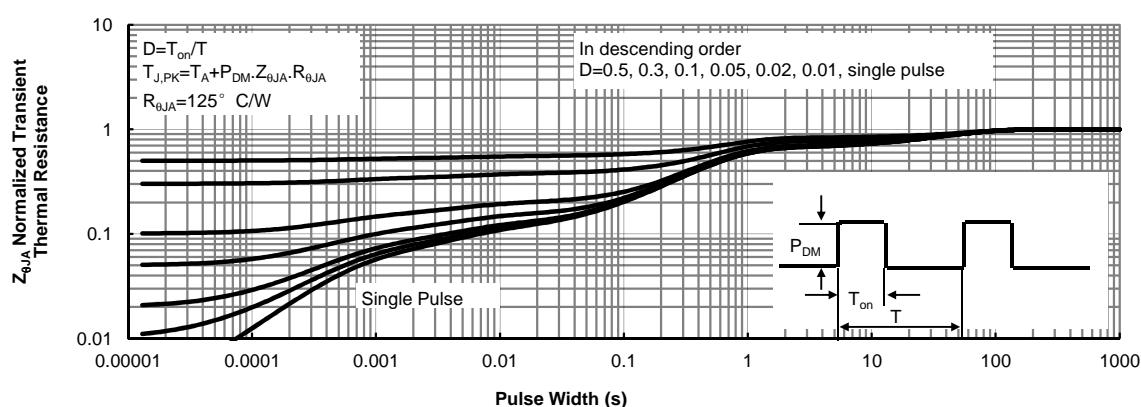
D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

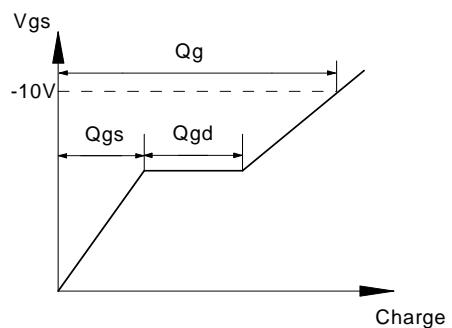
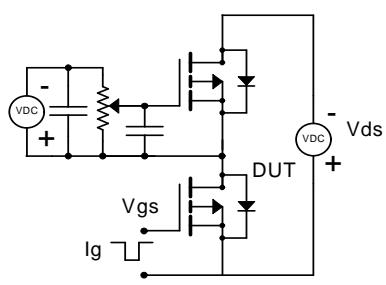
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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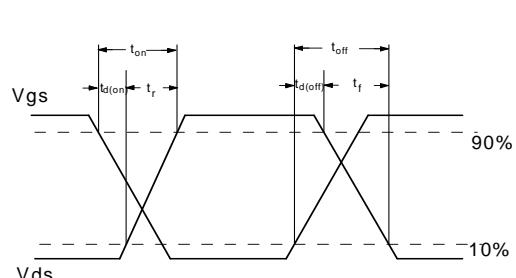
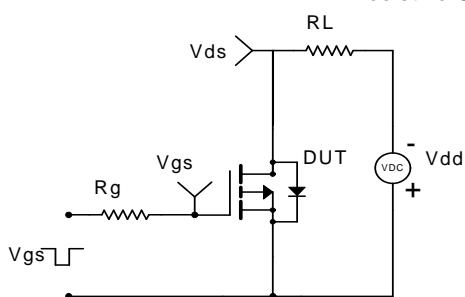
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Fig 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

